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Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/690,779	TAKEUCHI ET AL.	
Examiner	Art Unit	_
John S. Chu	1752	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST SEARCH IN FILE	9 (2005	gr.
Inventor search in EAST		